Please add claims 13-30 as follows:

--13. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 2, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

14. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 3, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

15. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 4, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

16. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 5, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

17. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 6, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

18. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 7, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

19. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 8, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

20. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 9, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

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21. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 10, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

22. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 2, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

23. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 3, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

24. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 4, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

25. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 5, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

26. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 6, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

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27. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 7, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

28. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 8, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

29. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 9, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

30. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 10, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.--